

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Application Number	10629301
	Filing Date	2003-07-28
	First Named Inventor	Lewis B. Aronson
	Art Unit	2613
	Examiner Name	Hanh Phan
	Attorney Docket Number	15436.247.2.1.3

U.S. PATENTS					
Examiner Initials*	Cite No.	Patent Number	Issue Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	4489477	1984-12-25	Chik et al	
	2	6977517	2005-12-20	Miao et al	
	3	7019548	2006-03-28	Miao et al	
	4	7155127	2006-12-26	Akimoto	
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U.S. PATENT APPLICATION PUBLICATIONS					
Examiner Initials*	Cite No.	Publication Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	20040076114	2004-04-22	Miriello	

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.	Foreign Patent Document	Country Code	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ¹
	1	2005006575	WO	2005-01-20	Finisar Corp		<input type="checkbox"/>
	2	1503232	EP	2004-07-27	Emcore Corp		
	3	2004135106	JP	2004-04-30	Hitachi Ltd		
	4	224406	TW	2004-11-21	Hon Hai Prec Ind Co Ltd		
	5	555297	TW	2003-09-21		Could not obtain copy	
	6	0203226	WO	2002-05-09			
	7	02704344	EP	2004-10-05			
	8	040117254	EP	2004-10-05			

FOREIGN OFFICE ACTION / NOTICE OF ALLOWANCE DOCUMENTS				
Examiner Initials*	Cite No.	Application Number	Mail Date	Document
	1			

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published	T ¹
	1	HAWTHORNE: "850nm Proton VCSEL Reliability Study" Technical Publications and Application Notes, Advances Optical Components (Finisar Corp), Issue 2, September 2001, pgs 1-7, Richardson, TX	<input type="checkbox"/>
	2	MECHERLE G S ET AL: "Considerations for Accelerated Laser Diode Life Testing" Proceedings of the Spie, Spie, Bellingham, VA, vol. 717, 1986, pgs 53-62	
	3	TEBBI O ET AL: "Comparitive study of accelrated testing models, applications in mechanics" 2001 IEEE International Conference on Systems Man and Cybernetics SMC 2001. Tucson, AZ Oct 7-10, 2001, IEEE International Conference on Systems, Man and Cybernetics, New York, NY: IEEE, US, vol 1 of 5 Oct 7, 2001 pgs 2099-2104	
	4	J.D. BARRY ET AL.: Thermally Accelerated Life Testing of Single Mode, Double-Heterostructure, AlGaAs Laser Diodes Operated Pulsed at 50 mW Peak Power" IEEE Journal of Quantum Electronics, vol. 21, no. 4 December 25, 1984 pgs 365-376	

OFFICE ACTION / NOTICE OF ALLOWANCE DOCUMENTS				
Examiner Initials*	Cite No.	Application Number	Mail Date	Document
	1	11118172	2008-09-04	Office Action
	2	10629302	2008-01-25	Restriction Requirement
	3	11073452	2008-08-07	Office Action
	4	11118172	2008-03-25	Office Action
	5	11073452	2007-12-31	Office Action
	6	10629302	2008-05-02	Office Action
	7	10884334	2008-01-16	Office Action
	8	10884334	2008-07-10	Office Action

EXAMINER SIGNATURE			
Examiner Signature		Date Considered	
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through a citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			
¹ Applicant is to place a check mark here if English language translation is attached.			